

Notice of References Cited

Application/Control No.

10/567,434

Applicant(s)/Patent Under
Reexamination
ABE ET AL.

Examiner

Hau V. Phan

Art Unit

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-7,110,869	09-2006	Tao et al.	701/34
*	B	US-7,255,186	08-2007	Wakuta et al.	180/65.2
*	C	US-7,223,200	05-2007	Kojima et al.	477/3
*	D	US-7,191,859	03-2007	Hashimoto, Takenori	180/65.4
*	E	US-7,081,060	07-2006	Hata et al.	475/5
*	F	US-6,455,947	09-2002	Lilley et al.	180/65.6
*	G	US-6,203,468	03-2001	Nitta et al.	477/5
*	H	US-6,146,302	11-2000	Kashiwase, Hajime	475/5
*	I	US-6,554,736	04-2003	Takano et al.	477/5
*	J	US-5,571,058	11-1996	Schmidt, Michael R.	475/5
*	K	US-5,513,719	05-1996	Moroto et al.	180/65.4
*	L	US-5,697,466	12-1997	Moroto et al.	180/65.2
*	M	US-6,155,364	12-2000	Nagano et al.	180/65.2

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)				
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	X					

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